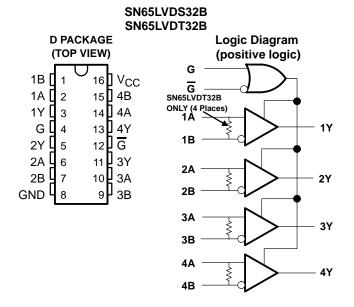
- Meets or Exceeds the Requirements of ANSI EIA/TIA-644 Standard for Signaling Rates[†] up to 400 Mbps
- Operates With a Single 3.3-V Supply
- -2-V to 4.4-V Common-Mode Input Voltage Range
- Differential Input Thresholds <50 mV With 50 mV of Hysteresis Over Entire Common-Mode Input Voltage Range
- Integrated 110-Ω Line Termination Resistors Offered With the LVDT Series
- Propagation Delay Times 4 ns (typ)
- Active Fail Safe Assures a High-Level Output With No Input
- Bus-Pin ESD Protection Exceeds 15 kV HBM
- Inputs Remain High-Impedance on Power Down
- Recommended Maximum Parallel Rate of 200 M-Transfers/s
- Available in Small-Outline Package With 1,27 mm Terminal Pitch
- Pin-Compatible With the AM26LS32, MC3486, or μA9637

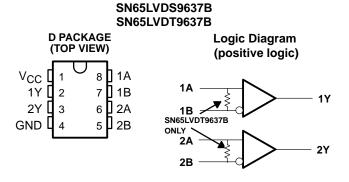
description

This family of differential line receivers offers improved performance and features that implement the electrical characteristics of low-voltage differential signaling (LVDS). LVDS is defined in the TIA/EIA-644 standard. This improved performance represents the second generation of receiver products for this standard, providing a better overall solution for the cabled environment. This generation of products is an extension to TI's overall product portfolio and is not necessarily a replacement for older LVDS receivers.

Improved features include an input commonmode voltage range 2 V wider than the minimum required by the standard. This will allow longer cable lengths by tripling the allowable ground noise tolerance to 3 V between a driver and receiver. TI has additionally introduced an even wider input common-mode voltage range of –4 to 5 V in their SN65LVDS/T33 and SN65LVDS/T34.



SN65LVDS3486B SN65LVDT3486B **D PACKAGE** Logic Diagram (TOP VIEW) (positive logic) SN65LVDT3486B 1B 16∏ Vcc ONLY (4 Places) 1A 🛮 2 15 4B 1Y 🛭 3 14 4A 1B 1.2EN 13 4Y 1.2EN L 2Y 🗓 12 3,4EN 5 2Y 3Y 2A 6 11 2B 2B 10 L ЗА **3A** 3B **GND** 9 8 **3Y** 3B 3.4EN 4A 4B





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

† Signaling rate, 1/t, where t is the minimum unit interval and is expressed in the units bits/s (bits per second)



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description (continued)

Precise control of the differential input voltage thresholds now allows for inclusion of 50 mV of input voltage hysteresis to improve noise rejection on slowly changing input signals. The input thresholds are still no more than ± 50 mV over the full input common-mode voltage range.

The high-speed switching of LVDS signals almost always necessitates the use of a line impedance matching resistor at the receiving-end of the cable or transmission media. The SN65LVDT series of receivers eliminates this external resistor by integrating it with the receiver. The nonterminated SN65LVDS series is also available for multidrop or other termination circuits.

The receivers can withstand ± 15 -kV human-body model (HBM) and ± 600 V-machine model (MM) electrostatic discharges to the receiver input pins with respect to ground without damage. This provides reliability in cabled and other connections where potentially damaging noise is always a threat.

The receivers also include a (patent pending) fail-safe circuit that will provide a high-level output within 600 ns after loss of the input signal. The most common causes of signal loss are disconnected cables, shorted lines, or powered-down transmitters. This prevents noise from being received as valid data under these fault conditions. This feature may also be used for wired-OR bus signaling.

The intended application of these devices and signaling technique is for point-to-point baseband data transmission over controlled impedance media of approximately 100 Ω . The transmission media may be printed-circuit board traces, backplanes, or cables. The ultimate rate and distance of data transfer is dependent upon the attenuation characteristics of the media and the noise coupling to the environment.

The SN65LVDS32B, SN65LVDT32B, SN65LVDS3486B, SN65LVDT3486B, SN65LVDS9637B, and SN65LVDT9637B are characterized for operation from -40°C to 85°C.

AVAILABLE OPTIONS

PART NUMBERT	NUMBER OF RECEIVERS	TERMINATION RESISTOR†	SYMBOLIZATION
SN65LVDS32BD	4	No	LVDS32B
SN65LVDT32BD	4	Yes	LVDT32B
SN65LVDS3486BD	4	No	LVDS3486
SN65LVDT3486BD	4	Yes	LVDT3486
SN65LVDS9637BD	2	No	DK637B
SN65LVDT9637BD	2	Yes	DR637B

[†] Add the suffix R for taped and reeled carrier.



Function Tables

SN65LVDS32B and SN65LVDT32B

DIFFERENTIAL INPUT	ENA	BLES	OUTPUT	
A-B	G	G	Υ	
V _{ID} ≥ -32 mV	H X	X L	H H	
-100 mV < V _{ID} ≤ -32 mV	H X	X L	?	
V _{ID} ≤ -100 mV	H X	X L	L L	
Х	Ш	Н	Z	
Open	H X	X L	H	

H = high level, L = low level, X = irrelevant,Z = high impedance (off), ? = indeterminate

SN65LVDS3486B and SN65LVDT3486B

DIFFERENTIAL INPUT	ENABLES	OUTPUT
A-B	EN	Υ
V _{ID} ≥ -32 mV	Н	Н
$-100 \text{ mV} < \text{V}_{\text{ID}} \le -32 \text{ mV}$	Н	?
$V_{ID} \le -100 \text{ mV}$	Н	L
X	L	Z
Open	Н	Н

H = high level, L = low level, X = irrelevant,Z = high impedance (off), ? = indeterminate

SN65LVDS9637B and SN65LVDT9637B

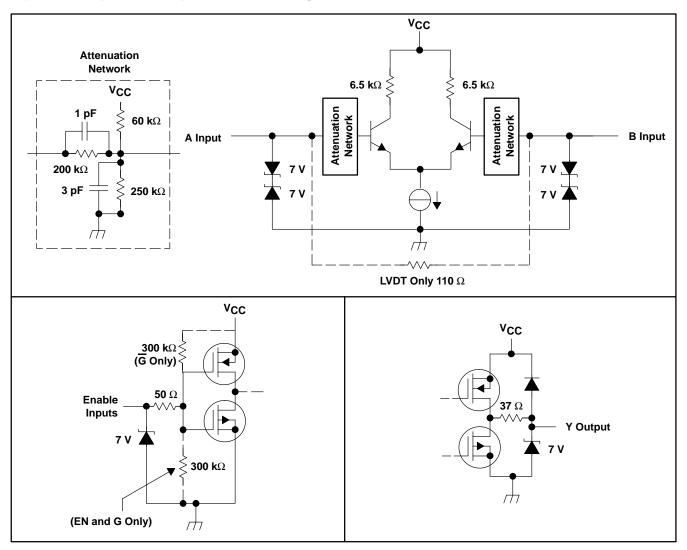
DIFFERENTIAL INPUT	OUTPUT
A-B	Υ
V _{ID} ≥ -32 mV	Н
-100 mV < V _{ID} ≤ -32 mV	?
V _{ID} ≤ -100 mV	L
Open	Н

H = high level, L = low level, ? = indeterminate



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equivalent input and output schematic diagrams



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absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Supply voltage range, V _{CC} (see Note 1)	-0.5 V to 4 V
Voltage range: Enables or Y	
A or B	
V _A – V _B (LVDT)	
Electrostatic discharge: A, B, and GND (see Note 2)	
Continuous power dissipation	
Storage temperature range	, ,
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	
Lead temperature 1,0 mm (1/10 mcm) nom case for 10 seconds	200 C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{\scriptsize A}} \le 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	OPERATING FACTOR [‡] ABOVE T _A = 25°C	T _A = 85°C POWER RATING
D8	725 mW	5.8 mW/°C	377 mW
D16	950 mW	7.6 mW/°C	494 mW

[‡] This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

recommended operating conditions

		М	IN N	ЮМ	MAX	UNIT
Supply voltage, V _{CC}			3	3.3	3.6	V
High-level input voltage, VIH	Enables		2			V
Low-level input voltage, V _{IL}	Enables				0.8	V
Magnitude of differential input valtage 1//- 1	LVDS	C	.1		3	V
Magnitude of differential input voltage, V _{ID} I	LVDT				0.8	V
Voltage at any bus terminal (separately or common-mode), VI or VIC			-2		4.4	V
Operating free-air temperature, Тд			40		85	°C



^{2.} Tested in accordance with MIL-STD-883C Method 3015.7.

SN65LVDS32B, SN65LVDT32B, SN65LVDS3486B SN65LVDT3486B, SN65LVDS9637B, SN65LVDT9637B HIGH-SPEED DIFFERENTIAL RECEIVERS SLLS440A - OCTOBER 2000 - REVISED MAY 2001

electrical characteristics over recommended operating conditions (unless otherwise noted)

PARAMETER			TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT
V _{IT1}	Positive-going differential input vo	ltage threshold	$V_{IB} = -2 \text{ V or } 4.4$	$V_{IB} = -2 \text{ V or } 4.4 \text{ V},$			50	mV
V _{IT2}	Negative-going differential input v	oltage threshold	See Figures 1 and 2		-50			IIIV
V _{IT3}	Differential input fail-safe voltage	threshold	See Table 1 and	Figure 5	-32		-100	mV
V _{ID(HYS)}	Differential input voltage hysteres VIT1 - VIT2	is,				50		mV
Vон	High-level output voltage		$I_{OH} = -4 \text{ mA}$		2.4			V
VOL	Low-level output voltage		$I_{OL} = 4 \text{ mA}$				0.4	V
		'32B or '3486B	G or EN at V _{CC} , Steady-state	No load,		16	23	
ICC	Supply current		G or EN at GND			1.1	5	mA
		'9637B	No load,	Steady-state		8	12	
			V _I = 0 V,	Other input open			±20	
		CNICELVIDO	V _I =2.4 V,	Other input open			±20	μΑ
	Input current (A or B inputs)	SN65LVDS	V _I = −2 V,	Other input open			±40	
l.			V _I = 4.4 V,	Other input open			±40	
†į			$V_I = 0 V$,	Other input open			±40	μΑ
		SN65LVDT	V _I =2.4 V,	Other input open			±40	
			V _I =–2 V,	Other input open			±80	
			V _I = 4.4 V,	Other input open			±80	
lD	Differential input current	SN65LVDS	V _{ID} = 100 mV, See Figure 1	V_{IC} = -2 V or 4.4 V,			±3	μΑ
	(IIA - IIB)	SN65LVDT	V _{ID} = 0.2 V,	V_{IC} = -2 V or 4.4 V	1.55		2.22	mA
	Power-off input current (A or B inputs) SN65LVDS SN65LVDT	CNGELVIDO	$V_{CC} = 0 V$	2.4 V,			±20	
l		SNOSEVDS	V_A or $V_B = -2 V C$ $V_{CC} = 0 V$	or 4.4 V,			±35	^
l(OFF)		CNGELVIDT	$V_{CC} = 0 V$	2.4 V,			±30	μА
		SINOSLVDT	V _A or V _B = -2 V o	or 4.4 V,			±50	
I _{IH} High-level input current (enables)		V _{IH} = 2 V				10	μΑ	
I _I L	Low-level input current (enables)		V _{IL} = 0.8 V				10	μΑ
loz	High-impedance output current						±10	μΑ
Cl			V _I = 0.4 sin (4E6	πt) + 0.5 V		5		pF

[†] All typical values are at 25°C and with a 3.3 V supply.



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switching characteristics over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP [†]	MAX	UNIT
tPLH	Propagation delay time, low-to-high-level output	See Figure 3	2.5	4	6	ns
tPHL	Propagation delay time, high-to-low-level output	See rigule 3	2.5	4	6	ns
^t d1	Delay time, fail-safe deactivate time	See Figures 3 and 6			9	ns
t _{d2}	Delay time, fail-safe activate time	See Figures 3 and 6	0.3		1.5	μs
t _{sk(p)}	Pulse skew (tpHL1 - tpLH1)			200		ps
tsk(o)	Output skew§			150		ps
t _{sk(pp)}	Part-to-part skew [‡]	C _L = 10 pF, See Figure 3			1	ns
t _r	Output signal rise time			0.8		ns
tf	Output signal fall time			0.8		ns
^t PHZ	Propagation delay time, high-level-to-high-impedance output			5.5	9	ns
tPLZ	Propagation delay time, low-level-to-high-impedance output	Soo Figure 4		4.4	9	ns
tPZH	Propagation delay time, high-impedance -to-high-level output	See Figure 4		3.8	9	ns
tPZL	Propagation delay time, high-impedance-to-low-level output			7	9	ns

[†] All typical values are at 25°C and with a 3.3-V supply.

‡ t_{sk(pp)} is the magnitude of the time difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

§ t_{sk(o)} is the magnitude of the time difference between the t_{PLH} or t_{PHL} of all receivers of a single device with all of their inputs driven together.

PARAMETER MEASUREMENT INFORMATION

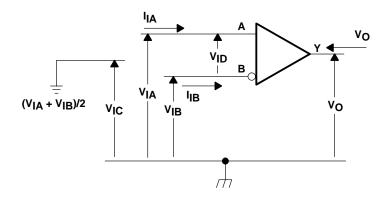
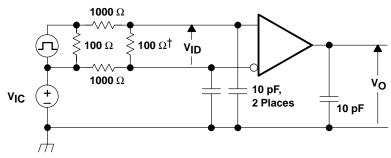
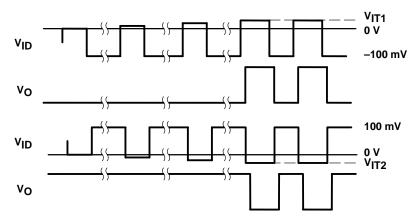


Figure 1. Voltage and Current Definitions



† Removed for testing the LVDT device

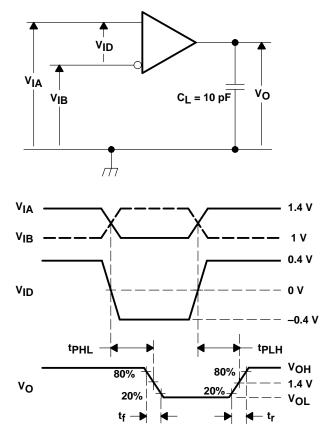


NOTE: Input signal of 3 Mpps, duration of 167 ns, and transition time of <1 ns.

Figure 2. V_{IT1} and V_{IT2} Input Voltage Threshold Test Circuit and Definitions



PARAMETER MEASUREMENT INFORMATION

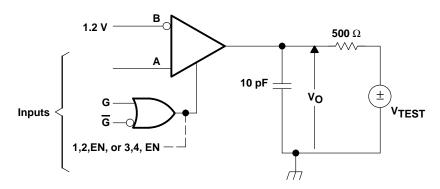


NOTE: All input pulses are supplied by a generator having the following characteristics: t_r or $t_f \le 1$ ns, pulse repetition rate (PRR) = 50 Mpps, Pulsewidth = 10 ± 0.2 ns . C_L includes instrumentation and fixture capacitance within 0,06 mm of the D.U.T.

Figure 3. Timing Test Circuit and Waveforms



PARAMETER MEASUREMENT INFORMATION



NOTE: All input pulses are supplied by a generator having the following characteristics: t_f or $t_f \le 1$ ns, pulse repetition rate (PRR) = 0.5 Mpps, Pulsewidth = 500 ± 10 ns . C_L includes instrumentation and fixture capacitance within 0,06 mm of the D.U.T.

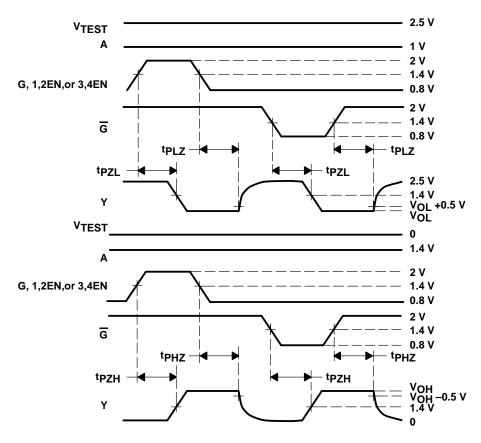


Figure 4. Enable/Disable Time Test Circuit and Waveforms

PARAMETER MEASUREMENT INFORMATION

Table 1. Receiver Minimum and Maximum V_{IT3}
Input Threshold Test Voltages

APPL	APPLIED VOLTAGES†			RESULTANT INPUTS		
V _{IA} (n	ıV)	V _{IB} (mV)	V _{ID} (mV)	V _{IC} (mV)	Output	
-200	0	-1900	-100	-1950	L	
-200	0	-1968	-32	-1984	Н	
430)	4400	-100	4350	L	
436	3	4400	-32	4384	Н	

[†] These voltages are applied for a minimum of 1.5 μs.

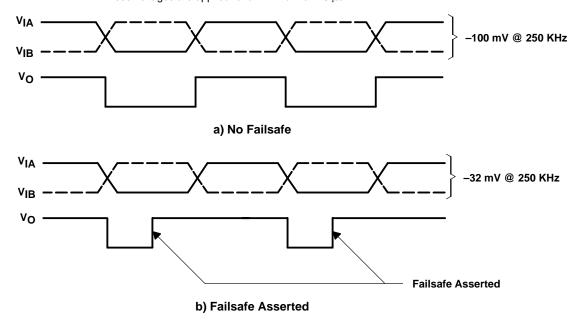


Figure 5. V_{IT3} Failsafe Threshold Test

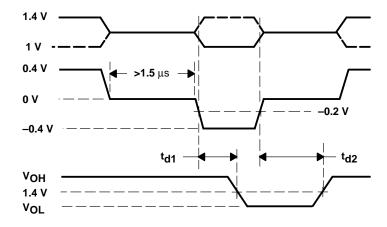
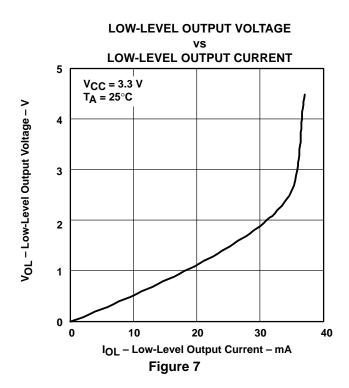
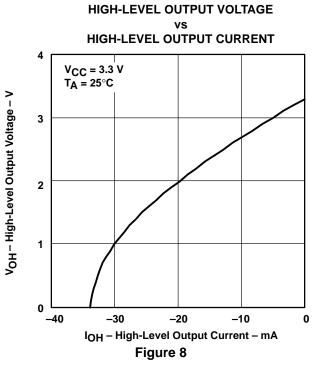


Figure 6. Waveforms for Failsafe Activate and Deactivate

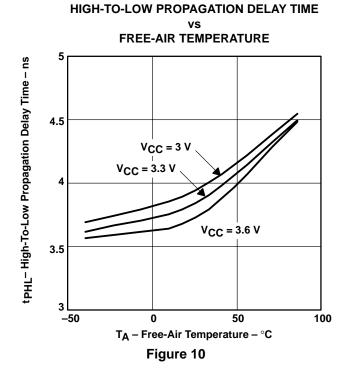


TYPICAL CHARACTERISTICS





LOW-TO-HIGH PROPAGATION DELAY TIME FREE-AIR TEMPERATURE tPLH- Low-To-High Propagation Delay Time - ns 4.5 $V_{CC} = 3 V$ $V_{CC} = 3.3 V$ $V_{CC} = 3.6 V$ 3.5 -50 100 T_A - Free-Air Temperature - °C Figure 9

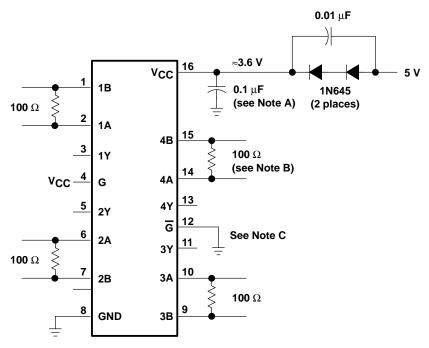


TYPICAL CHARACTERISTICS

SUPPLY CURRENT FREQUENCY 140 120 $V_{CC} = 3.3 V$ 100 I_{CC}- Supply Current - mA 80 $V_{CC} = 3.6 \text{ V}$ 60 V_{CC} = 3 V 40 20 0 100 150 200 f – Switching Frequency – MHz

Figure 11

APPLICATION INFORMATION



- NOTES: A. Place a 0.1-μF Z5U ceramic, mica or polystyrene dielectric, 0805 size, chip capacitor between V_{CC} and the ground plane. The capacitor should be located as close as possible to the device terminals.
 - B. The termination resistance value should match the nominal characteristic impedance of the transmission media with ±10%.
 - C. Unused enable inputs should be tied to V_{CC} or GND as appropriate.

Figure 12. Operation with 5-V Supply

related information

IBIS modeling is available for this device. Please contact the local TI sales office or the TI Web site at www.ti.com for more information.

For more application guidelines, please see the following documents:

- Low-Voltage Differential Signalling Design Notes (TI literature number SLLA014)
- Interface Circuits for TIA/EIA-644 (LVDS) (SLLA038)
- Reducing EMI With LVDS (SLLA030)
- Slew Rate Control of LVDS Circuits (SLLA034)
- Using an LVDS Receiver With RS-422 Data (SLLA031)
- Evaluating the LVDS EVM (SLLA033)



APPLICATION INFORMATION

terminated failsafe

A differential line receiver commonly has a fail-safe circuit to prevent it from switching on input noise. Current LVDS fail-safe solutions require either external components with subsequent reduction in signal quality or integrated solutions with limited application. This family of receivers has a new integrated fail-safe that solves the limitations seen in present solutions. A detailed theory of operation is presented in application note *The Active Fail-Safe Feature of the SN65LVDS32A*, literature number SLLA082.

Figure 13 shows one receiver channel with active fail-safe. It consists of a main receiver that can respond to a high-speed input differential signal. Also connected to the input pair are two fail-safe receivers that form a window comparator. The window comparator has a much slower response than the main receiver and detects when the input differential falls below 80 mV. A 600-ns fail-safe timer filters the window comparator outputs. When fail-safe is asserted, the fail-safe logic drives the main receiver output to logic high.

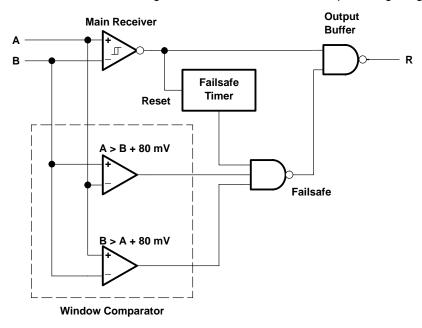


Figure 13. Receiver With Terminated Failsafe

APPLICATION INFORMATION

ECL/PECL-to-LVTTL conversion with TI's LVDS receiver

The various versions of emitter-coupled logic (i.e. ECL, PECL and LVPECL) are often the physical layer of choice for system designers. Designers know of the established technology and that it is capable of high-speed data transmission. In the past, system requirements often forced the selection of ECL. Now technologies like LVDS provide designers with another alternative. While the total exchange of ECL for LVDS may not be a design option, designers have been able to take advantage of LVDS by implementing a small resistor divider network at the input of the LVDS receiver. TI has taken the next step by introducing a wide common-mode LVDS receiver (no divider network required) which can be connected directly to an ECL driver with only the termination bias voltage required for ECL termination ($V_{\rm CC}-2$ V).

Figures 14 and 15 show the use of an LV/PECL driver driving 5 meters of CAT–5 cable and being received by TI's wide common-mode receiver and the resulting eye pattern. The values for R3 are required in order to provide a resistor path to ground for the LV/PECL driver. With no resistor divider, R1 simply needs to match the characteristic load impedance of 50 Ω . The R2 resistor is a small value and is intended to minimize any possible common-mode current reflections.

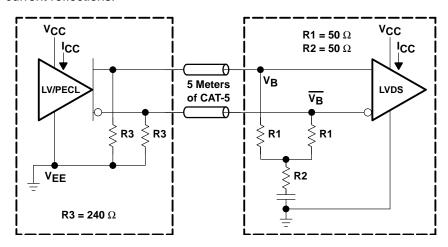


Figure 14. LVPECL or PECL to Remote Wide Common-Mode LVDS Receiver

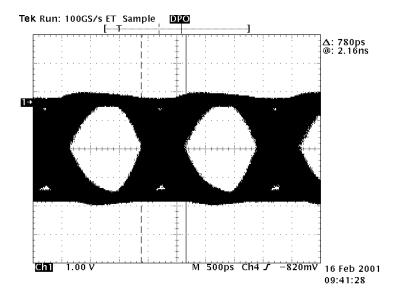


Figure 15. LV/PECL to Remote SN65LVDS32B at 500 Mbps Receiver Output (CH1)



APPLICATION INFORMATION

test conditions

- $V_{CC} = 3.3 \text{ V}$
- $T_A = 25^{\circ}\text{C}$ (ambient temperature) All four channels switching simultaneously with NRZ data. Scope is pulse-triggered simultaneously with NRZ data.

equipment

- Tektronix PS25216 programmable power supply
- Tektronix HFS 9003 stimulus system
- Tektronix TDS 784D 4-channel digital phosphor oscilloscope DPO

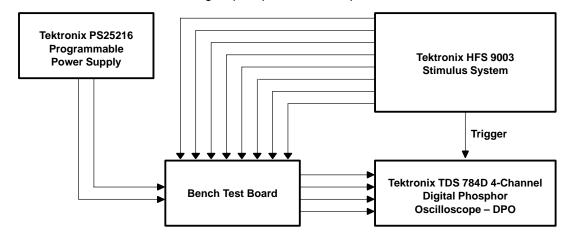


Figure 16. Equipment Setup

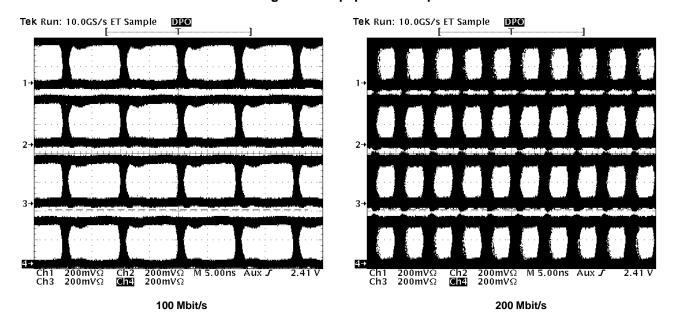


Figure 17. Typical Eye Pattern SN65LVDS32B

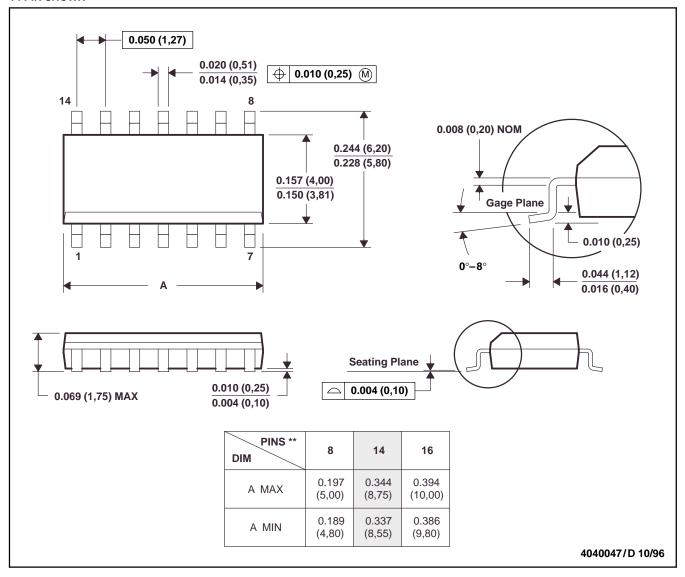


MECHANICAL DATA

D (R-PDSO-G**)

14 PIN SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).

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